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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

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Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









August 2007

FDP8443

N-Channel PowerTrench[®] MOSFET

40V, **80A**, **3.5m**Ω

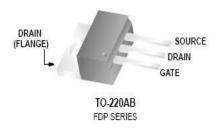
Features

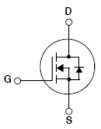
- Typ $r_{DS(on)}$ = 2.7m Ω at V_{GS} = 10V, I_D = 80A
- Typ $Q_{q(10)}$ = 142nC at V_{GS} = 10V
- Low Miller Charge
- Low Q_{rr} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)
- Qualified to AEC Q101
- RoHS Compliant

Applications

- Automotive Engine Control
- Powertrain Management
- Solenoid and Motor Drivers
- Electronic Steering
- Integrated Starter / Alternator
- Distributed Power Architecture and VRMs
- Primary Switch for 12V Systems







MOSFET Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain to Source Voltage		40	V
V_{GS}	Gate to Source Voltage		±20	V
	Drain Current Continuous (T _C < 144°C, V _{GS} = 10V)		80	
I_D	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 62^{\circ}C/W$)		20	Α
	Pulsed		See Figure 4	
E _{AS}	Single Pulse Avalanche Energy	(Note 1)	531	mJ
П	Power Dissipation		188	W
P_D	Derate above 25°C		1.25	W/°C
T _J , T _{STG}	Operating and Storage Temperature		-55 to +175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case		0.8	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	(Note 2)	62	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP8443	FDP8443	TO-220AB	Tube	N/A	50 units

Test Conditions

Min

Тур

Units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Parameter

Off Ch	aracteristics					
B_{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	40	-	-	V
1	Zero Gate Voltage Drain Current	$V_{DS} = 32V$,	-	-	1	μΑ
DSS	Zero Gate Voltage Drain Gurrent	$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	250	μΑ
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$	-	-	±100	nA

On Characteristics

Symbol

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2	2.8	4	V
		$I_D = 80A, V_{GS} = 10V$	-	2.7	3.5	
r _{DS(on)}	Drain to Source On Resistance	$I_D = 80A, V_{GS} = 10V,$ $T_J = 175$ °C	-	4.7	6.1	mΩ

Dynamic Characteristics

C _{iss}	Input Capacitance)/ OF)/)/	2) (-	9310	-	pF
Coss	Output Capacitance	[⊣] V _{DS} = 25V, V _{GS} = (_− f = 1MHz	JV,	-	800	-	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/12		-	510	-	pF
R_G	Gate Resistance	$V_{GS} = 0.5V, f = 1MI$	Hz	-	0.9	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	V _{GS} = 0 to 10V		-	142	185	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0$ to $2V$	V _{DD} = 20V	-	17.5	23	nC
Q _{gs}	Gate to Source Gate Charge		I _D = 35A	-	36	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau		$I_g = 1mA$	-	18.8	-	nC
Q_{gd}	Gate to Drain "Miller" Charge			-	32	-	nC

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units

Switching Characteristics (V_{GS} = 10V)

t _{on}	Turn-On Time		1	-	58	ns
t _{d(on)}	Turn-On Delay Time	.,	1	18.4	-	ns
t _r	Rise Time	$V_{DD} = 20V, I_D = 35A$ $V_{GS} = 10V, R_{GS} = 2\Omega$	1	17.9	-	ns
$t_{d(off)}$	Turn-Off Delay Time	V _{GS} = 10V, K _{GS} = 252	1	55	-	ns
t _f	Fall Time		1	13.5	-	ns
t_{off}	Turn-Off Time		1	-	109	ns

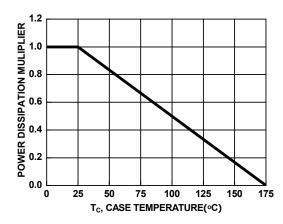
Drain-Source Diode Characteristics

V _{SD} Source to Drain Diode Voltage	Source to Drain Diade Voltage	I _{SD} = 35A	-	0.8	1.25	\/
	I _{SD} = 15A	-	0.8	1.0	v	
t _{rr}	Reverse Recovery Time	I _{SD} = 35A, dI _{SD} /dt = 100A/μs	-	42	55	ns
Q _{rr}	Reverse Recovery Charge	ISD - 33A, diSD/dt - 100A/μS	-	48	62	nC

1: Starting T_J = 25°C, L = 0.26mH, I_{AS} = 64A. 2: Pulse width = 100s.

This product has been designed to meet the extreme test conditions and environment demanded by the automotive industry. For a copy of the requirements, see AEC Q101 at: http://www.aecouncil.com/
All Fairchild Semiconductor products are manufactured, assembled and tested under ISO9000 and QS9000 quality systems certification.

Typical Characteristics



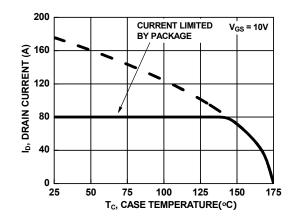


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

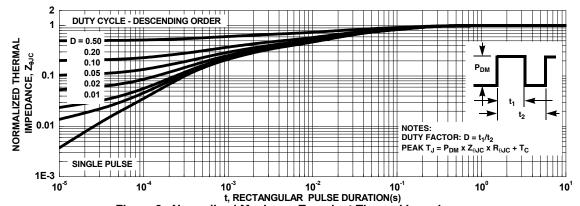


Figure 3. Normalized Maximum Transient Thermal Impedance

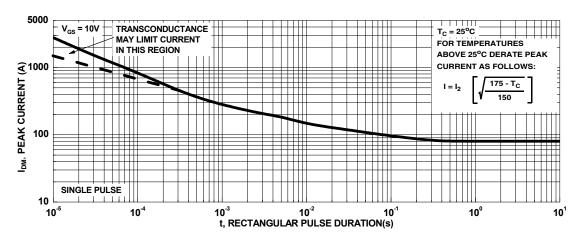


Figure 4. Peak Current Capability

Typical Characteristics

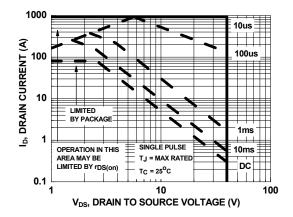
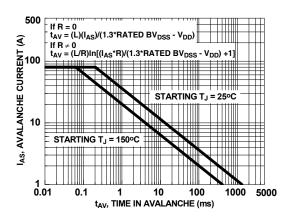


Figure 5. Forward Bias Safe Operating Area



NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability

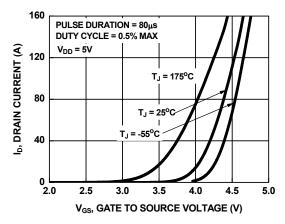


Figure 7. Transfer Characteristics

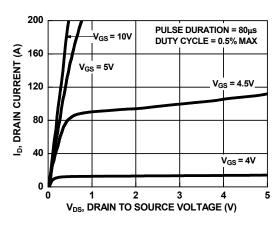


Figure 8. Saturation Characteristics

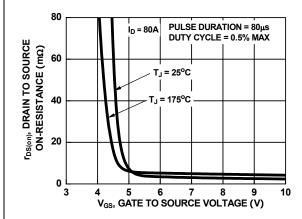


Figure 9. Drain to Source On-Resistance Variation vs Gate to Source Voltage

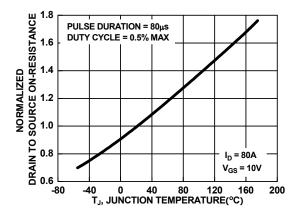


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

Typical Characteristics

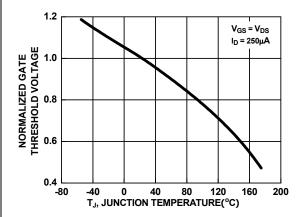


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

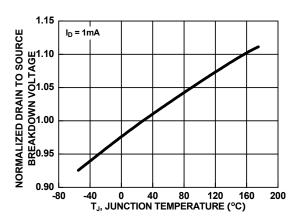


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

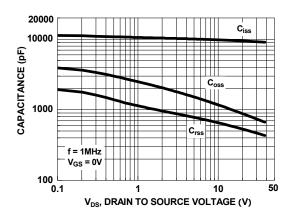


Figure 13. Capacitance vs Drain to Source Voltage

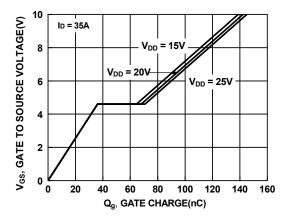


Figure 14. Gate Charge vs Gate to Source Voltage





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		This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
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